



4/20/2008

**RELIABILITY MONITOR REPORT
FOR**

Chartered 0.35 μ m Silicon Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS2155	DS3112	DS33R41
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The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 9048** **FITS: 12.6**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2007 and 3/31/2008 .

Process Information:

Process Description: Chartered 0.35µm Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	0712	DS3112	125C, 3.5 VOLTS	1000 HRS	77	0	
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
TEMP CYCLE, 5' RAMP, 10' DWELL	0708	DS33R41	-40C TO +125C	1000 CYS	77	0	
TEMP CYCLE, 5' RAMP, 10' DWELL	0729	DS2155	-55C TO 125C	1000 CYS	77	0	
Total:						0	

FAILURE RATE: **MTTF (YRS): 9048** **FITS: 12.6**